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- 10:00-10:10**    **Welcome and Overview (final agenda)**  
*European Space Agency/ESTEC, NL - Reno Harboe Sørensen*
- 10:10-10:40**    **Particle Test of Xilinx Virtex-II FPGA using XTMR Mitigation Technique**  
  
**Summary of Radiation Data Available on Actel, Xilinx and Atmel FPGA**  
*Saab Ericsson Space, Sweden/ESA-ESTEC, NL – Fredrik Stuesson*
- 10:40-11:00**    **Modelling of Radiation SEE on Components**  
*LIP, Lisbon, Portugal – Ana Keating*
- 11:00-11:20**    **Radiation Testing of AMI 0.35 um and UMC 0.18 um – Radiation Tolerant and Normal Layout Devices.**  
*SRON, The Netherlands – Steven Leussink*
- 11:20-11:40**    **On-going and Planned RADFET Developments**  
*Tyndall National Institute, Ireland – Aleksandar Jaksic*
- 11:40-12:00**    **Proton Testing of Micro Advanced Stellar Compass**  
*DTU, Denmark – Helle Karina Aage, Peter Buch Guldager*
- 12:00-13:30**    **Lunch Break**

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- 13:30-14:20**    **Radiation Evaluation of ST Test Structures in 130 nm, 90 nm and 65 nm Technologies.**  
*STMicroelectronics, Crolles, France – Philippe Roche (RHS)*
- 14:20-14:40**    **Radiation Testing of Innovative GPS-Receiver - Two ASIC IC's designed in AMS 0.35 um Technology.**  
*Nemerix, Switzerland – Angelo Consoli/Francesco Piazza*
- 14:40-15:00**    **Proton Irradiation of the STAR1000 Active Pixel Sensor: Preliminary Results on NIEL Scaling.**  
*ESA/ESTEC, The Netherlands – Ludovic Duvet*
- 15:00-15:20**    **Random Telegraph Signals in CCDs and Active Pixel Sensors.**  
*SSTL, UK – Gordon R. Hopkinson*
- 15:20-15:40**    **Coffee Break**

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| 15:40-16:00 | <b>Laser Single Event Effects Studies - Phase III</b><br><i>MBDA UK Ltd, United Kingdom – Andrew Chugg</i>                                                                                                                                                     |
| 16:00-16:20 | <b>Heavy Ion SEE Testing of Delta VPT DC-DC Converters for PROBA-II.</b><br><i>ESA/ESTEC, The Netherlands – Sven Landstrom (RHS)</i>                                                                                                                           |
| 16:20-16:40 | <b>Linear Energy Transfer Measurements of Heavy Ions in Silicon</b><br><i>University of Jyväskylä, Finland – Ari Virtanen/Arto Javanainen</i>                                                                                                                  |
| 16:40-17:00 | <b>Low Dose Rate TID Testing of Candidate Components for ESA Projects.</b><br><i>ESA/ESTEC, The Netherlands – Ali Mohammedzadeh</i>                                                                                                                            |
| 17:00-17:30 | <b>News from the European Component Irradiation Facilities,<br/>PIF, HIF, RADEF &amp; ECF.</b><br><i>ECIF – Wojtek Hajdas                      Guy Berger</i><br><i>                                         Ari Virtanen                      Bob Nickson</i> |
| 17:30       | <b>End of Day 1 Presentations</b>                                                                                                                                                                                                                              |
| 18:00       | <b>Start of Social Programme – Trip to Leuven</b>                                                                                                                                                                                                              |

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| <b>09:30-09:40</b> | <b>Overview (final agenda) and Introduction to CNES Presentations.</b><br><i>ESA/ESTEC, NL - Reno Harboe Sørensen</i><br><i>CNES, France – Francoise Bezerra/Robert Ecoffet</i> |  |
| <b>09:40-10:05</b> | <b>Compendium of 2006 CNES Radiation Evaluation Tests Results on Commercial Integrated Circuits</b><br><i>CNES, France - Florence Malou</i>                                     |                                                                                     |
| <b>10:05-10:30</b> | <b>Advances in Research on Radiation Effects on Optic and Optoelectronic Components</b><br><i>ONERA, France – T. Nuns or CEM2, France - P. Signoret/L. Trousselier</i>          |                                                                                     |
| <b>10:30-11:00</b> | <b>Switched Dose Rates as an Alternative Method for ELDRS Testing</b><br><i>CEM2, France - Jérôme Boch or Frederic Saigné</i>                                                   |                                                                                     |
| <b>11:00-11:30</b> | <b>New Insights into SEGR and SEB mechanisms in power MOSFETs</b><br><i>EADS-Astrium, France - Daniel Peyre</i>                                                                 |                                                                                     |
| <b>11:30-12:00</b> | <b>Probing SEE Sensitive Volumes Using a Focused Laser Beam</b><br><i>EADS-CCR, France - Cecile Weulersse</i>                                                                   |                                                                                     |
| <b>12:00-13:30</b> | <b>Lunch Break</b>                                                                                                                                                              |                                                                                     |

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- 13:30-13:50**    **SEE Testing of Advanced Memories –  
Part I: Test Approach and Sample Preparation.**  
*HIREX Engineering, France – Francois-Xavier Guerre / Gregoire Lewis*
- 13:50-14:10**    **SEE Testing of Advanced Memories –  
Part II: Heavy Ion Results on SDRAMs and Preliminary Results on DDR-II.**  
*HIREX Engineering, France – Francois-Xavier Guerre / Gregoire Lewis*
- 14:10-14:40**    **Compendium of 2006 CNES Radiation Evaluation Tests   Results on  
Commercial Memories**  
*CNES, France – Jean Bertrand*
- 14:40-15:00**    **Further Heavy Ion and Proton SEE Evaluation of High Capacity  
FLASH Memory Devices for SafeGuard Data Recorder.**  
*IDA, Braunschweig, Germany – M. Brüggemann/H. Schmidt/H. Michalik/Gliem*
- 15:00-15:20**    **Study of Heavy Ion Radiation Effects in FLASH Memories**  
*University of Padova, Italy – Alessandro Paccagnella/Giorgio Cellere*
- 15:20-15:40**    **Coffee Break**

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- 15:40-16:00**    **European Component Initiative: STM Power MOS Development**  
*ESA/ESTEC, NL – Ralf de Marino*
- 16:00-16:20**    **GAIA PEM Radiation Test Program – SEL testing of 13 IC's**  
*MSSL, UK – Phil Guttridge/Mark Hailey (or RHS)*
- 16:20-16:40**    **Upgrade of the Light-Ion Irradiation Facility (LIF) at Louvain-la-Neuve**  
*UCL/CRC, Louvain-la-Neuve, Belgium – Guy Berger*
- 16:40-16:45**    **Introduction to Tours – LIF & Ion Beam Application S.A. (IBA).**  
*UCL/CRC, Louvain-la-Neuve, Belgium – Guy Berger*
- 16:45-17:45**    **Tours: LIF/IBA and IBA/LIF – 2 groups**
- 17:45**            **End of Day 2 Presentations**
- 18:00**            **Start of Social Programme – Trip to Brussels**